

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

YD/T 3433-2018

**Technical requirements and testing method for wavelength
selective reflector embedded in ONU optical module used in
Optical Time Domain Reflector meter (OTDR) measurement**

用于OTDR测试的ONU光模块内置波长选择性反射器技术要求和测试方法

(English Translation)

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What this standard covers

This standard specifies the abbreviations, terms and definitions, technical requirements, test methods, etc. of the built-in wavelength selective reflector for ONU optical modules used in OTDR testing. This standard applies to wavelength selective reflectors built into ONU optical modules in passive optical network (PON) systems. The OTDR center wavelengths used are 1490nm, 1625nm and 1650nm. Optical modules of other dedicated telecommunications networks have built-in wavelength selective reflectors, or wavelength selective reflectors that use other center wavelengths such as 1577 nm for OTDR testing.

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